BFP405F

Low profile wideband silicon NPN RF bipolar transistor

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Product description

The BFP405F is a low noise device based on a grounded emitter (SIEGET™) that is part of Infineon's established fourth generation RF bipolar transistor family. Its transition frequency f_T of 25 GHz and low current characteristics make the device suitable for oscillators up to 12 GHz. It remains cost competitive without compromising on ease of use.

Feature list

- Minimum noise figure NF_{min} = 1.25 dB at 1.8 GHz, 2 V, 2 mA
- High gain G_{ms} = 22.5 dB at 1.8 GHz, 2 V, 5 mA
- OIP_3 = 14 dBm at 1.8 GHz, 2 V, 5 mA

Product validation

Qualified for industrial applications according to the relevant tests of JEDEC47/20/22.

Potential applications

- Radio-frequency oscillators
- Broadband low noise amplifiers (LNAs) for CATV, DVB-T, DAB/DMB and FM/AM radio
- LNAs for sub-1 GHz ISM band applications

Device information

Table 1 Part information

Product name / Ordering code	Package	Pin configuration				Marking	Pieces / Reel
BFP405F / BFP405FH6327XTSA1	TSFP-4-1	1 = B	2 = E	3 = C	4 = E	ALs	3000

***Attention*: ESD (Electrostatic discharge) sensitive device, observe handling precautions**

Table of contents

1 Absolute maximum ratings

Table 2 Absolute maximum ratings at T_A = 25 °C (unless otherwise specified)

Parameter	Symbol	Values		Unit	Note or test condition
		Min.	Max.		
Collector emitter voltage	V_{CEO}	–	4.5	V	Open base
			4.1		T_A = -55 °C, open base
Collector emitter voltage	V_{CES}		15		E-B short circuited
Collector base voltage	V_{CBO}		15		Open emitter
Emitter base voltage	V_{EBO}		1.5		Open collector
Base current	I_B		3	mA	–
Collector current	I_C		25		
Total power dissipation [1)]	P_{tot}		75	mW	$T_S \leq 112$ °C
Junction temperature	T_J		150	°C	–
Storage temperature	T_{Stg}	-55			

Attention**: **Stresses above the max. values listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Exceeding only one of these values may cause irreversible damage to the integrated circuit.

1 T_S is the soldering point temperature. T_S is measured on the emitter lead at the soldering point of the PCB.

2 Thermal characteristics

Table 3 Thermal resistance

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Junction - soldering point	R_{thJS}	–	500	–	K/W	–

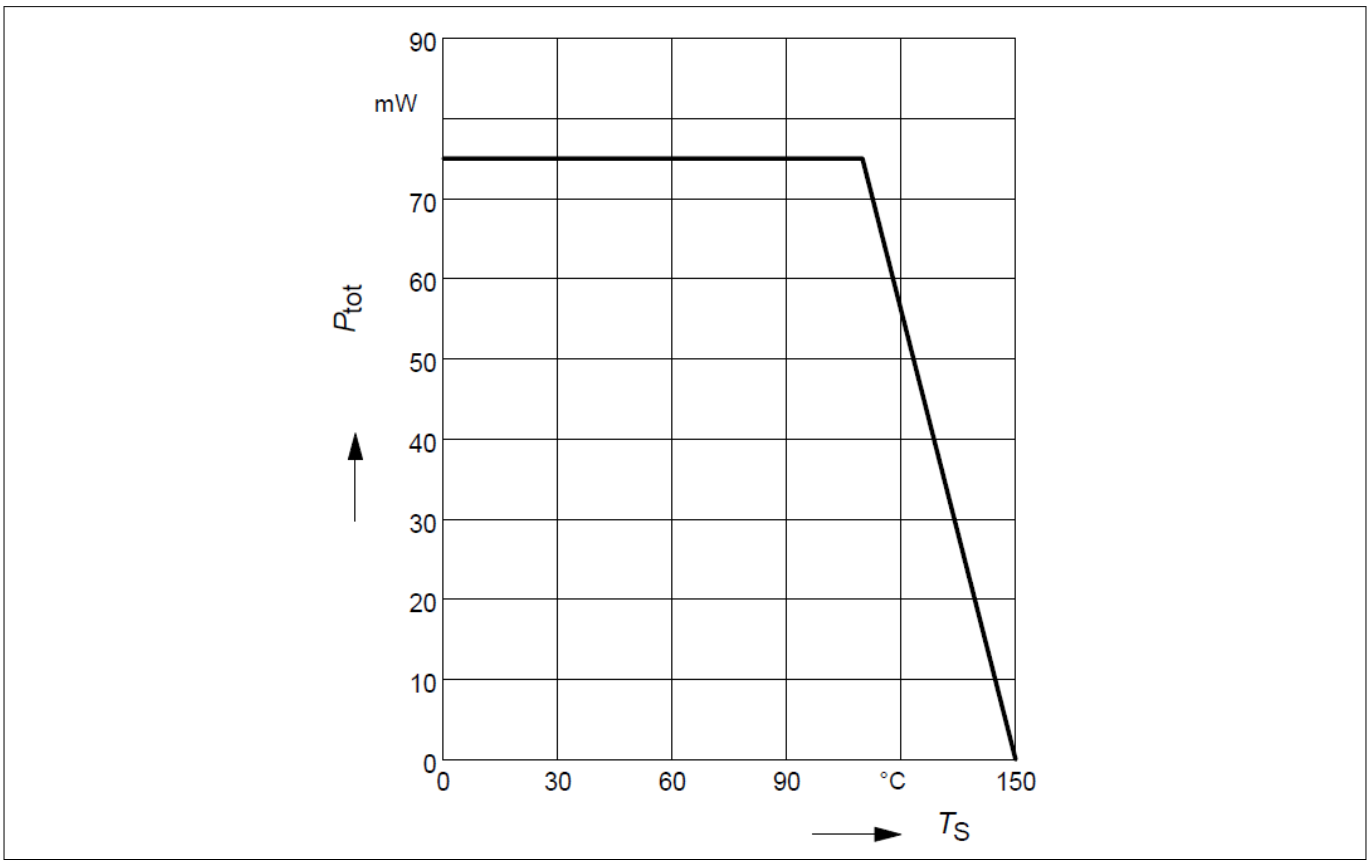

Figure 1 Total power dissipation $P_{tot} = f(T_S)$

3 Electrical characteristics

3.1 DC characteristics

Table 4 DC characteristics at T_A = 25 °C

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Collector emitter breakdown voltage	$V_{(BR)CEO}$	4	5	–	V	I_C = 1 mA, I_B = 0, open base
Collector emitter leakage current	I_{CES}	–	–	10 [2)]	µA	V_{CE} = 15 V, V_{BE} = 0, E-B short circuited
Collector base leakage current	I_{CBO}			100 [2)]	nA	V_{CB} = 5 V, I_E = 0, open emitter
Emitter base leakage current	I_{EBO}			1 [2)]	µA	V_{EB} = 0.5 V, I_C = 0, open collector
DC current gain	h_{FE}	60	95	130		V_{CE} = 4 V, I_C = 5 mA, pulse measured

3.2 General AC characteristics

Table 5 General AC characteristics at T_A = 25 °C

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Transition frequency	f_T	18	25	–	GHz	V_{CE} = 3 V, I_C = 10 mA, f = 2 GHz
Collector base capacitance	C_{CB}	–	0.05	0.1	pF	V_{CB} = 2 V, V_{BE} = 0, f = 1 MHz, emitter grounded
Collector emitter capacitance	C_{CE}		0.2	–		V_{CE} = 2 V, V_{BE} = 0, f = 1 MHz, base grounded
Emitter base capacitance	C_{EB}		0.25			V_{EB} = 0.5 V, V_{CB} = 0, f = 1 MHz, collector grounded

2 Maximum values not limited by the device but by the short cycle time of the 100% test.

3.3 Frequency dependent AC characteristics

Measurement setup is a test fixture with Bias-T's in a 50 Ω system, T_A = 25 °C.

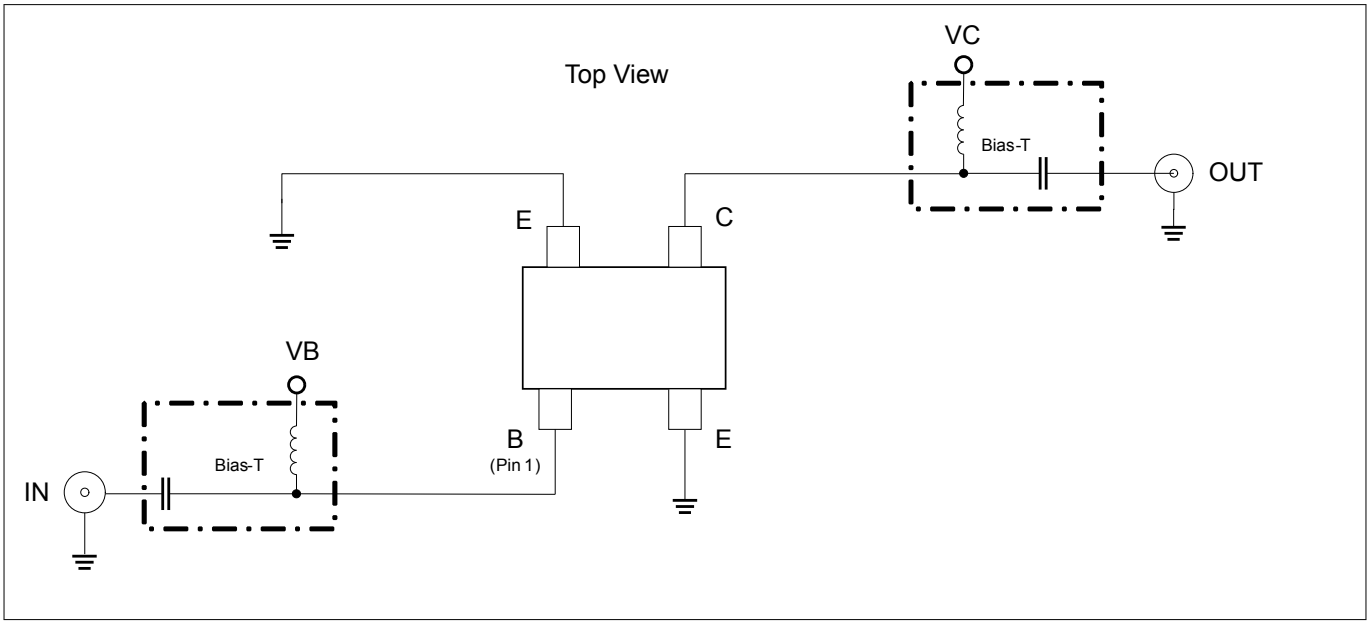

Figure 2 Testing circuit

Table 6 AC characteristics, V_{CE} = 2 V, f = 1.8 GHz

Parameter	Symbol	Values			Unit	Note or test condition
		Min.	Typ.	Max.		
Power gain		–		–	dB	
• Maximum power gain	G_{ms}		22.5			I_C = 5 mA
• Transducer gain	$\|S_{21}\|^2$		18			
Noise figure						
• Minimum noise figure	NF_{min}		1.25			I_C = 2 mA
Linearity					dBm	
• 3rd order intercept point at output	OIP_3		14			I_C = 5 mA, Z_S = Z_L = 50 Ω
• 1 dB gain compression point at output	OP_{1dB}		0			

Note: $G_{ms} = |S_{21} / S_{12}|$ for $k < 1$; $G_{ma} = |S_{21} / S_{12}|(k-(k^2-1)^{1/2})$ for $k > 1$. In order to get the NF_{min} values stated in this chapter, the test fixture losses have been subtracted from all measured results. OIP_3 value depends on termination of all intermodulation frequency components. Termination used for this measurement is 50 Ω from 0.1 MHz to 6 GHz.

4 Package information TSFP-4-1

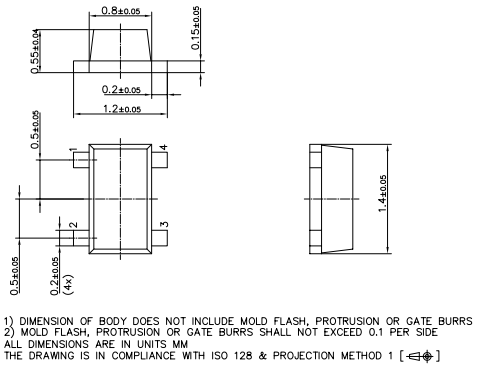

Figure 3 Package outline

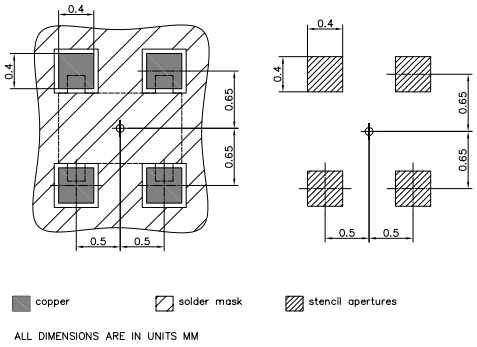

Figure 4 Foot print

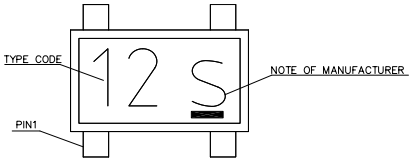

Figure 5 Marking layout example

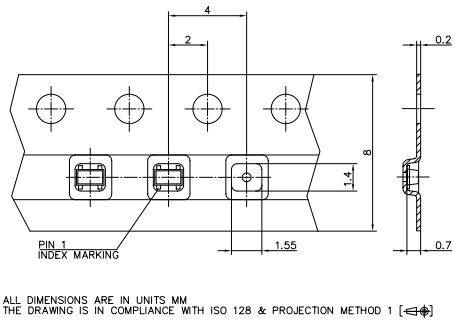

Figure 6 Tape dimensions

Revision history

Document version	Date of release	Description of changes
Revision 2.0	2019-01-25	New datasheet layout.